

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/647,272	SEKI ET AL.		
Examiner	Art Unit		
Thinh H. Nauven	2861		

	SEAR	CHED	
Class	Subclass	Date	Examiner
347	19,22-23 29-30,32	5/17/2005	TN
	_		
			-
			-

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
347	19,29	5/17/2005	TN	
		]		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
,		DATE	EXMR		
Search Updated		5/17/2005	TN		
· ·					